

Supply Chain Explorer: Defect inspection tools

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Defect inspection tools

Defect inspection tools include brightfield inspection tools (using light to scan the wafer), darkfield inspection tools (using lasers), e-beam inspection tools (using electrons), and optical and scanning electron microscopes.

Notable supplier companies

- ASML - Netherlands
- Applied Materials - United States
- Hitachi - Japan
- KLA - United States
- RSIC - China (mainland)
- SMEE - China (mainland)